	Hits	Ref #	Search Text	Type
1	174140	S1	image$1 with (sensor or ccd or cmos)	BRS
2	3173	S2	S1 same calibrat$3	BRS
3	1603	S3	S1 with calibrat$3	BRS
4	5	S4	S3 same (defect$3 adj pixel)	BRS
5	5	S5	S4 same (defect$3 adj pixel)	BRS
6	2	S6	S4 same sheet	BRS
7	0	S7	S4 same (white and black)	BRS
8	2	S8	S4 same (white or light)	BRS
9	2	S9	S4 same averag$3	BRS
10	8493	S10	image$1 with (cmos)	BRS
11	73	S11	S10 same calibrat$3	BRS
12	12	S12	("4381890" | "4473289" | "4739394" | "5541656" | "5619029" | "5701015" | "5740480" | "5781807" | "5808669" | "5818525" | "5821993" | "5918192").PN.	BRS
13	5	S13	("4754329" | "4928300" | "5574664" | "5606365" | "5633678").PN.	BRS
14	174140	S14	image$1 with (sensor or ccd or cmos)	BRS
15	12092	S15	S14 and calibrat$3	BRS
16	60	S17	S16 and (defective adj pixel)	BRS
17	10	S18	("5122881" | "5144447" | "5293240" | "5296696" | "5311319" | "5335008" | "5336879" | "5453783" | "5488415" | "5502488").PN.	BRS
18	8182	S19	S15 and (averag$3 or ratio)	BRS
19	1166	S20	S14 and (accumulation adj time)	BRS
20	34	S21	S20 and (defective adj pixel)	BRS
21	552	S22	S14 and (defective adj pixel)	BRS
22	286	S23	S22 and (dark or black)	BRS
23	203	S24	S23 and (averag$3 or ratio)	BRS
24	14	S25	("2026376" | "4167754" | "4288817" | "4383170" | "4481539" | "4488178" | "4535363" | "4541016" | "4543601" | "4567524" | "4581649" | "4595954" | "4633317").PN.	BRS
25	10	S26	("3830972" | "4178510" | "4567525" | "4589028" | "4602291" | "4694342" | "5047863" | "5499114" | "5748768" | "5832055").PN.	BRS
26	9	S27	("4216503" | "4602291" | "4698685" | "4833533" | "4835606" | "4839866" | "4894721" | "4912558" | "4920428").PN.	BRS
27	174140	S28	image$1 with (sensor or ccd or cmos)	BRS

	Hits	Ref #	Search Text	Type
28	3173	S29	S28 same calibrat$3	BRS
29	174140	S30	image$1 with (sensor or ccd or cmos)	BRS
30	12092	S31	S30 and calibrat$3	BRS
31	156	S32	S29 and (dark adj current)	BRS
32	7	S33	S32 and (defect$3 adj pixel)	BRS
33	38	S34	S29 and (defect$3 adj pixel)	BRS
34	9	S35	("4216503" | "4602291" | "4698685" | "4833533" | "4835606" | "4839866" | "4894721" | "4912558" | "4920428").PN.	BRS
35	12	S36	("4216503" | "4314281" | "4534059" | "4590520" | "4601058" | "4602291" | "4628352" | "4633314" | "4639781" | "4660082" | "4698685" | "4701784").PN.	BRS
36	310	S37	scanner adj calibration	BRS
37	4	S38	S37 and (defect$3 adj pixel)	BRS
38	0	S39	S36 and (defect$3 adj pixel)	BRS
39	5	S40	("4193093" | "4253120" | "4343021" | "4376289" | "4399464").PN.	BRS
40	3	S41	("3904818" | "4032976" | "4189751").PN.	BRS
41	8493	S42	image$1 with (cmos)	BRS
42	97	S43	S42 and (defect$3 adj pixel)	BRS
43	17	S44	S43 and calibrat$3	BRS
44	10	S45	("5122881" | "5144447" | "5293240" | "5296696" | "5311319" | "5335008" | "5336879" | "5453783" | "5488415" | "5502488").PN.	BRS
45	24	S47	S46 same calibrat$3	BRS
46	282	S48	S46 same (white or light)	BRS
47	119	S49	S48 same (dark or black)	BRS
48	13	S50	S49 same averag$3	BRS
49	510	S51	S46 same detect$3	BRS
50	39	S52	S51 same averag$3	BRS
51	1254	S46	image$1 same (defect$3 adj pixel)	BRS
52	212	S53	348/246,247.ccls.	BRS
53	84	S54	S53 and detect	BRS
54	187	S55	S53 and (white or light)	BRS
55	120	S56	S55 and (dark or black)	BRS
56	4	S57	("3904818" | "4443817" | "4481539" | "4488178").PN.	BRS

	Hits	Ref #	Search Text	Type
57	14	S58	("3800078" | "4216503" | "4343021" | "4486781" | "4602277" | "4602291" | "4698685" | "4731661" | "4760464" | "4839729" | "4903316" | "4912558" | "4970598" | "4979042").PN.	BRS
58	77	S59	S56 and averag$3	BRS
59	3	S60	(("6415063") or ("6529622") or ("6381374")).PN.	IS&R
60	5	S61	("4858013" | "5047863" | "5617461" | "5790694" | "6087673").PN.	BRS
61	174140	S62	image$1 with (sensor or ccd or cmos)	BRS
62	3173	S63	S62 same calibrat$3	BRS
63	131	S64	S63 same ratio	BRS
64	365	S65	S62 same (defect$3 adj pixel)	BRS
65	12	S66	S65 same ratio	BRS
66	174140	S67	image$1 with (sensor or ccd or cmos)	BRS
67	552	S68	S67 and (defective adj pixel)	BRS
68	184	S69	S68 and ratio	BRS
69	305	S70	S67 same (defective adj pixel)	BRS
70	8	S71	S70 same ratio	BRS
71	1360	S72	image$1 adj ratio	BRS
72	2	S73	S72 same (defective adj pixel)	BRS
73	4164	S74	image$1 with variance	BRS
74	1	S75	S74 same (defective adj pixel)	BRS
75	80	S76	S67 and (dead adj pixel)	BRS
76	49	S77	S76 and (ratio or difference)	BRS
77	41	S78	S76 and ratio	BRS
78	478	S79	pixel adj ratio	BRS
79	91	S80	S79 and (first adj image)	BRS
80	56	S81	S80 and (second adj image)	BRS
81	7	S82	S79 same (first adj image)	BRS
82	5	S83	S82 same (second adj image)	BRS
83	1	S84	("5886353").PN.	IS&R

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